

April 1988 Revised September 2000

# 74F175 Quad D-Type Flip-Flop

#### **General Description**

The 74F175 is a high-speed quad D-type flip-flop. The device is useful for general flip-flop requirements where clock and clear inputs are common. The information on the D inputs is stored during the LOW-to-HIGH clock transition. Both true and complemented outputs of each flip-flop are provided. A Master Reset input resets all flip-flops, independent of the Clock or D inputs, LOW.

#### **Features**

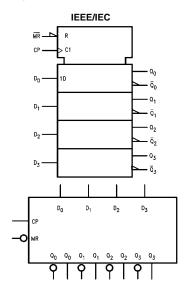
- Edge-triggered D-type inputs
- Buffered positive edge-triggered clock
- Asynchronous common reset
- True and complement output

### **Ordering Code:**

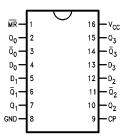
Order Number	Package Number	Package Description
74F175SC	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow
74F175SJ	M16D	16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F175PC	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

#### **Logic Symbols**



#### **Connection Diagram**



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DS009490

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## **Unit Loading/Fan Out**

Dia Nama	Paradintian.	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>	
Pin Names	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>	
D <sub>0</sub> -D <sub>3</sub>	Data Inputs	1.0/1.0	20 μA/-0.6 mA	
СР	Clock Pulse Input (Active Rising Edge)	1.0/1.0	20 μA/-0.6 mA	
MR	Master Reset Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
$Q_0-Q_3$	True Outputs	50/33.3	−1 mA/20 mA	
$\overline{Q}_0$ – $\overline{Q}_3$	Complement Outputs	50/33.3	−1 mA/20 mA	

#### **Functional Description**

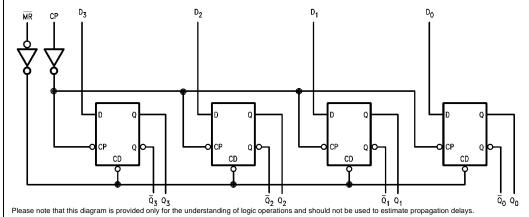
The 74F175 consists of four edge-triggered D-type flipflops with individual D inputs and Q and  $\overline{Q}$  outputs. The Clock and Master Reset are common. The four flip-flops will store the state of their individual D inputs on the LOW-to-HIGH clock (CP) transition, causing individual Q and  $\overline{Q}$  outputs to follow. A LOW input on the Master Reset ( $\overline{MR}$ ) will force all Q outputs LOW and  $\overline{Q}$  outputs HIGH independent of Clock or Data inputs. The 74F175 is useful for general logic applications where a common Master Reset and Clock are acceptable.

#### **Truth Table**

	Inputs	Outputs			
MR CP		D <sub>n</sub>	Q <sub>n</sub>	$\overline{\mathbf{Q}}_{\mathbf{n}}$	
L	Х	Х	L	Н	
Н	~	Н	Н	L	
Н	~	L	L	Н	

H = HIGH Voltage Level

#### **Logic Diagram**



L = LOW Voltage Level

X = Immaterial

<sup>✓ =</sup> LOW-to-HIGH Clock Transition

### **Absolute Maximum Ratings**(Note 1)

-65°C to +150°C Storage Temperature -55°C to +125°C Ambient Temperature under Bias

Junction Temperature under Bias -55°C to +150°C V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

Standard Output -0.5V to  $V_{CC}$ 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I<sub>OL</sub> (mA)

#### **Recommended Operating Conditions**

0°C to +70°C Free Air Ambient Temperature Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

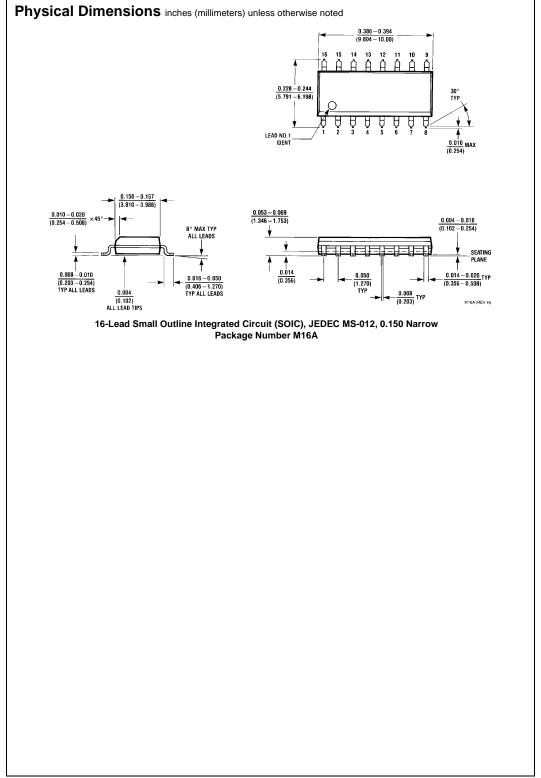
Symbol	Parameter		Min	Тур	Max	Units	V <sub>CC</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V <sub>IL</sub>	Input LOW Voltage				8.0	V		Recognized as a LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH	10% V <sub>CC</sub>	2.5			V	Min	I <sub>OH</sub> = -1 mA
	Voltage	$5\% V_{CC}$	2.7			V	IVIIII	$I_{OH} = -1 \text{ mA}$
V <sub>OL</sub>	Output LOW	10% V <sub>CC</sub>			0.5	V	Min	I <sub>OL</sub> = 20 mA
	Voltage				0.5	V	IVIIII	10L - 20 IIIA
I <sub>IH</sub>	Input HIGH				5.0	μА	Max	V <sub>IN</sub> = 2.7V
	Current				3.0	μΛ	IVIAX	V IN - 2.7 V
I <sub>BVI</sub>	Input HIGH Current				7.0	μА	Max	V <sub>IN</sub> = 7.0V
	Breakdown Test				7.0	μΛ	IVICA	V <sub>IN</sub> = 1.0 V
I <sub>CEX</sub>	Output HIGH				50	μА	Max	V <sub>OUT</sub> = V <sub>CC</sub>
	Leakage Current				30	μΛ	IVIAX	VOUT - VCC
V <sub>ID</sub>	Input Leakage		4.75			V	0.0	I <sub>ID</sub> = 1.9 μA
	Test		4.75			V	0.0	All Other Pins Grounded
l <sub>OD</sub>	Output Leakage				3.75	μА	0.0	V <sub>IOD</sub> = 150 mV
	Circuit Current				3.73	μΛ	0.0	All Other Pins Grounded
I <sub>IL</sub>	Input LOW Current				-0.6	mA	Max	V <sub>IN</sub> = 0.5V
los	Output Short-Circuit Current		-60		-150	mA	Max	V <sub>OUT</sub> = 0V
Icc	Power Supply Current			22.5	34.0	mA	Max	CP =
								$D_n = \overline{MR} = HIGH$

# **AC Electrical Characteristics**

Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$			$T_{A} = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50$ pF		Units
		Min	Тур	Max	Min	Max	Min	Max	
f <sub>MAX</sub>	Maximum Clock Frequency	100	140		80		100		MHz
t <sub>PLH</sub>	Propagation Delay	4.0	5.0	6.5	3.5	8.5	4.0	7.5	
t <sub>PHL</sub>	CP to Q <sub>n</sub> or Q <sub>n</sub>	4.0	6.5	8.5	4.0	10.5	4.0	9.5	ns
t <sub>PHL</sub>	Propagation Delay  MR to Q <sub>n</sub>	4.5	9.0	11.5	4.5	15.0	4.5	13.0	ns
t <sub>PLH</sub>	Propagation Delay MR to Qn	4.0	6.5	8.0	4.0	10.0	4.0	9.0	ns

# **AC Operating Requirements**

Symbol	Parameter	$T_A = +25$ °C $V_{CC} = +5.0$ V		$T_A = -55^{\circ}C$ to $+125^{\circ}C$ $V_{CC} = +5.0V$		$T_A = 0$ °C to $+70$ °C $V_{CC} = +5.0V$		Units
		Min	Max	Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	3.0		3.0		3.0		
t <sub>S</sub> (L)	D <sub>n</sub> to CP	3.0		3.0		3.0		ns
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	1.0		1.0		1.0		
t <sub>H</sub> (L)	D <sub>n</sub> to CP	1.0		2.0		1.0		
t <sub>W</sub> (H)	CP Pulse Width	4.0		4.0		4.0		no
$t_W(L)$	HIGH or LOW	5.0		5.0		5.0		ns
t <sub>W</sub> (L)	MR Pulse Width, LOW	5.0		5.0		5.0		ns
t <sub>REC</sub>	Recovery Time, MR to CP	5.0		5.0		5.0		ns



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16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide Package Number M16D

0.60±0.15

-1.25 ---

SEATING PLANE

DETAIL A

C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

M16DRevB1

#### Physical Dimensions inches (millimeters) unless otherwise noted (Continued) 0.740 - 0.780 0.090 (18.80 - 19.81)(2.286) 16 15 14 13 12 11 10 9 16 15 INDEX ARFA 0.250 ± 0.010 $\overline{(6.350 \pm 0.254)}$ PIN NO. 1 PIN NO. 1 1 2 3 4 5 6 7 8 1 2 IDENT OPTION 01 OPTION 02 0.065 $\frac{0.130 \pm 0.005}{(3.302 \pm 0.127)}$ $\frac{0.060}{(1.524)}$ TYP 4º TYP OPTIONAL (1.651)0.300 - 0.320(7.620 - 8.128) 0.145 - 0.200 $\overline{(3.683 - 5.080)}$ 95° ± 5° 0.008 - 0.016 (0.203 - 0.406) TYP 0.020 $\frac{0.280}{(7.112)}$ (0.508)0.125 - 0.150 (3.175 - 3.810) $0.030 \pm 0.015$ $(0.762 \pm 0.381)$ 0.014 - 0.0230.100 ± 0.010 (0.325 +0.040 -0.015 (0.356 - 0.584)0.050 ± 0.010 $(2.540 \pm 0.254)$ N16E (REV F) $(1.270 \pm 0.254)$

16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N16E

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